Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | NG, KEE YEAN | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0043926	04-2002	Takahashi et al.	313/503
	В	US-			
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	D	US-			=1
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